## **Kuang Sheng**

## List of Publications by Citations

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|-----|---|-----|-----------|
| 125 | A Bidirectional LLC Resonant Converter With Automatic Forward and Backward Mode Transition. <i>IEEE Transactions on Power Electronics</i> , <b>2015</b> , 30, 757-770   | 7.2 | 133       |
| 124 | High-Voltage and High-\$I_{text {ON}}/I_{text {OFF}}\$ Vertical GaN-on-GaN Schottky Barrier Diode With Nitridation-Based Termination. <i>IEEE Electron Device Letters</i> , <b>2018</b> , 39, 572-575                     | 4.4 | 76        |
| 123 | High Temperature Stability and the Performance Degradation of SiC MOSFETs. <i>IEEE Transactions on Power Electronics</i> , <b>2014</b> , 29, 2329-2337  | 7.2 | 74        |
| 122 | A Bidirectional Three-Level LLC Resonant Converter With PWAM Control. <i>IEEE Transactions on Power Electronics</i> , <b>2016</b> , 31, 2213-2225   | 7.2 | 63        |
| 121 | Dynamic on-State Resistance Test and Evaluation of GaN Power Devices Under Hard- and Soft-Switching Conditions by Double and Multiple Pulses. <i>IEEE Transactions on Power Electronics</i> , <b>2019</b> , 34, 1044-1053 | 7.2 | 56        |
| 120 | . IEEE Transactions on Power Electronics, <b>2019</b> , 34, 10193-10205   | 7.2 | 54        |
| 119 | A 3600 V/80 A SeriesParallel-Connected Silicon Carbide MOSFETs Module With a Single External Gate Driver. <i>IEEE Transactions on Power Electronics</i> , <b>2014</b> , 29, 2296-2306                                     | 7.2 | 52        |
| 118 | An All-SiC High-Frequency Boost DCDC Converter Operating at 320 LC Junction Temperature. <i>IEEE Transactions on Power Electronics</i> , <b>2014</b> , 29, 5091-5096  | 7.2 | 48        |
| 117 | Design and Experimental Study of 4H-SiC Trenched Junction Barrier Schottky Diodes. <i>IEEE Transactions on Electron Devices</i> , <b>2014</b> , 61, 2459-2465   | 2.9 | 44        |
| 116 | Impact of Substrate Bias Polarity on Buffer-Related Current Collapse in AlGaN/GaN-on-Si Power Devices. <i>IEEE Transactions on Electron Devices</i> , <b>2017</b> , 64, 5048-5056   | 2.9 | 42        |
| 115 | Dynamic On-Resistance in GaN Power Devices: Mechanisms, Characterizations, and Modeling. <i>IEEE Journal of Emerging and Selected Topics in Power Electronics</i> , <b>2019</b> , 7, 1425-1439                            | 5.6 | 40        |
| 114 | Current-Collapse-Free and Fast Reverse Recovery Performance in Vertical GaN-on-GaN Schottky Barrier Diode. <i>IEEE Transactions on Power Electronics</i> , <b>2019</b> , 34, 5012-5018                                    | 7.2 | 40        |
| 113 | Circulating Current and ZVS-on of a Dual Active Bridge DC-DC Converter: A Review. <i>IEEE Access</i> , <b>2019</b> , 7, 50561-50572   | 3.5 | 38        |
| 112 | Fluorine-Implanted Termination for Vertical GaN Schottky Rectifier With High Blocking Voltage and Low Forward Voltage Drop. <i>IEEE Electron Device Letters</i> , <b>2019</b> , 40, 1040-1043                             | 4.4 | 37        |
| 111 | Cryogenic and high temperature performance of 4H-SiC power MOSFETs 2013,  |     | 34        |
| 110 | SILICON CARBIDE SCHOTTKY BARRIER DIODE. <i>International Journal of High Speed Electronics and Systems</i> , <b>2005</b> , 15, 821-866  | 0.5 | 34        |
| 109 | An Analytical Model With 2-D Effects for 4H-SiC Trenched Junction Barrier Schottky Diodes. <i>IEEE Transactions on Electron Devices</i> , <b>2014</b> , 61, 4158-4165   | 2.9 | 33        |

| 108 | Characteristics and Application of Normally-Off SiC-JFETs in Converters Without Antiparallel Diodes. <i>IEEE Transactions on Power Electronics</i> , <b>2013</b> , 28, 4850-4860                            | 7.2             | 26 |  |
|-----|---|-----------------|----|--|
| 107 | Design and experimental demonstration of 1.35 kV SiC super junction Schottky diode <b>2016</b> ,  |                 | 25 |  |
| 106 | Evaluation of reverse recovery characteristic of silicon carbide metalBxideBemiconductor field-effect transistor intrinsic diode. <i>IET Power Electronics</i> , <b>2016</b> , 9, 969-976                   | 2.2             | 22 |  |
| 105 | Experimental Demonstration and Analysis of a 1.35-kV 0.92-m \$Omega cdot text {cm}^{2}\$ SiC Superjunction Schottky Diode. <i>IEEE Transactions on Electron Devices</i> , <b>2018</b> , 65, 1458-1465       | 2.9             | 19 |  |
| 104 | Investigation on single pulse avalanche failure of SiC MOSFET and Si IGBT. <i>Solid-State Electronics</i> , <b>2019</b> , 152, 33-40  | 1.7             | 18 |  |
| 103 | 1.2-kV 4H-SiC Merged PiN Schottky Diode With Improved Surge Current Capability. <i>IEEE Journal of Emerging and Selected Topics in Power Electronics</i> , <b>2019</b> , 7, 1496-1504                       | 5.6             | 17 |  |
| 102 | Theoretical Performance Limit of the IGBT. IEEE Transactions on Electron Devices, 2017, 64, 4184-4192   | 2.9             | 16 |  |
| 101 | Optimization of gate geometry towards high-sensitivity AlGaN/GaN pH sensor. <i>Talanta</i> , <b>2019</b> , 205, 120°  | 1342            | 15 |  |
| 100 | Comparison and analysis of short circuit capability of 1200V single-chip SiC MOSFET and Si IGBT <b>2016</b> ,   |                 | 15 |  |
| 99  | 4H-SiC Super-Junction JFET: Design and Experimental Demonstration. <i>IEEE Electron Device Letters</i> , <b>2020</b> , 41, 445-448  | 4.4             | 14 |  |
| 98  | Improved Device Performance in AlGaN/GaN HEMT by Forming Ohmic Contact With Laser Annealing. <i>IEEE Electron Device Letters</i> , <b>2018</b> , 39, 1137-1140  | 4.4             | 14 |  |
| 97  | Analysis on reverse recovery characteristic of SiC MOSFET intrinsic diode 2014,   |                 | 14 |  |
| 96  | Photon-Enhanced Conductivity Modulation and Surge Current Capability in Vertical GaN Power Rectifiers <b>2019</b> ,   |                 | 12 |  |
| 95  | Investigation of 1200 V SiC MOSFETs' Surge Reliability. <i>Micromachines</i> , <b>2019</b> , 10,  | 3.3             | 12 |  |
| 94  | A 10kV/200A SiC MOSFET module with series-parallel hybrid connection of 1200V/50A dies <b>2015</b> ,  |                 | 11 |  |
| 93  | High-Temperature Characterization of a 1.2-kV SiC MOSFET Using Dynamic Short-Circuit Measurement Technique. <i>IEEE Journal of Emerging and Selected Topics in Power Electronics</i> , <b>2020</b> , 8, 215 | 5- <u>5</u> :62 | 11 |  |
| 92  | Switching Performance Analysis of Vertical GaN FinFETs: Impact of Interfin Designs. <i>IEEE Journal of Emerging and Selected Topics in Power Electronics</i> , <b>2021</b> , 9, 2235-2246                   | 5.6             | 11 |  |
| 91  | Analysis of stray inductance's influence on SiC MOSFET switching performance <b>2014</b> ,  |                 | 10 |  |

| 90 | 1200-V 4H-SiC Merged p-i-n Schottky Diodes With High Avalanche Capability. <i>IEEE Transactions on Electron Devices</i> , <b>2020</b> , 67, 3679-3684  | 2.9 | 10 |
|----|--|-----|----|
| 89 | Design and Application of High-Voltage SiC JFET and Its Power Modules. <i>IEEE Journal of Emerging and Selected Topics in Power Electronics</i> , <b>2016</b> , 4, 780-789   | 5.6 | 10 |
| 88 | Conductivity Modulation in Vertical GaN PiN Diode: Evidence and Impact. <i>IEEE Electron Device Letters</i> , <b>2021</b> , 42, 300-303  | 4.4 | 9  |
| 87 | Failure Mechanism Analysis of SiC MOSFETs in Unclamped Inductive Switching Conditions <b>2019</b> ,  |     | 8  |
| 86 | Suppressing Methods of Parasitic Capacitance Caused Interference in a SiC MOSFET Integrated Power Module. <i>IEEE Journal of Emerging and Selected Topics in Power Electronics</i> , <b>2019</b> , 7, 745-752      | 5.6 | 8  |
| 85 | Bandgap engineering of monolayer MoS2 under strain: A DFT study. <i>Journal of the Korean Physical Society</i> , <b>2015</b> , 66, 1789-1793   | 0.6 | 8  |
| 84 | Tunable bandgap of monolayer black phosphorus by using vertical electric field: A DFT study.<br>Journal of the Korean Physical Society, <b>2015</b> , 66, 1031-1034  | 0.6 | 7  |
| 83 | Trench Termination With SiO2-Encapsulated Dielectric for Near-Ideal Breakdown Voltage in 4H-SiC Devices. <i>IEEE Electron Device Letters</i> , <b>2018</b> , 39, 1900-1903   | 4.4 | 7  |
| 82 | Investigation on single pulse avalanche failure of 900V SiC MOSFETs 2018,  |     | 6  |
| 81 | Investigation of Surge Current Capability of GaN E-HEMTs in The Third Quadrant: The Impact of P-GaN Contact. <i>IEEE Journal of Emerging and Selected Topics in Power Electronics</i> , <b>2019</b> , 7, 1465-1474 | 5.6 | 6  |
| 80 | Design and Characterization of Area-Efficient Trench Termination for 4H-SiC Devices. <i>IEEE Journal of Emerging and Selected Topics in Power Electronics</i> , <b>2019</b> , 7, 1519-1526                         | 5.6 | 6  |
| 79 | An Empirical Study on the Impact of Collaborative R&D Networks on Enterprise Innovation Performance Based on the Mediating Effect of Technology Standard Setting. <i>Sustainability</i> , <b>2019</b> , 11, 7249   | 3.6 | 6  |
| 78 | Improving Surge Current Capability of SiC Merged PiN Schottky Diode by Adding Plasma Spreading Layers. <i>IEEE Transactions on Power Electronics</i> , <b>2020</b> , 35, 11316-11320                               | 7.2 | 6  |
| 77 | Ab initio study of tunable band gap of monolayer and bilayer phosphorene by the vertical electronic field. <i>Journal Wuhan University of Technology, Materials Science Edition</i> , <b>2017</b> , 32, 213-216    | 1   | 5  |
| 76 | Enhancement-mode GaN-on-Silicon MOS-HEMT using pure wet etch technique 2015,   |     | 5  |
| 75 | A Comparative Study of Silicon Carbide Merged PiN Schottky Diodes with Electrical-Thermal Coupled Considerations. <i>Materials</i> , <b>2020</b> , 13,   | 3.5 | 5  |
| 74 | The Leakage Mechanism of the Package of the AlGaN/GaN Liquid Sensor. <i>Materials</i> , <b>2020</b> , 13,  | 3.5 | 5  |
| 73 | Dynamic on-state resistance evaluation of GaN devices under hard and soft switching conditions <b>2018</b> ,   |     | 5  |

| 72 | Design and experimental analysis of a 1 kW, 800 kHz all-SiC boost DC-DC converter <b>2014</b> ,  |     | 5 |
|----|--|-----|---|
| 71 | Modeling of a 1200 V 6 a SiC bipolar junction transistor <b>2013</b> ,   |     | 5 |
| 70 | Power electronic transformer for dc power distribution network <b>2014</b> ,   |     | 5 |
| 69 | Gate drive investigations of IGBT modules with SiC-Schottky freewheeling diodes 2013,  |     | 5 |
| 68 | Heat Transfer Characteristics and Flow Pattern Visualization for Flow Boiling in a Vertical Narrow Microchannel. <i>Journal of Electronic Packaging, Transactions of the ASME</i> , <b>2019</b> , 141,           | 2   | 5 |
| 67 | Hybrid Termination With Wide Trench for 4H-SiC Super-Junction Devices. <i>IEEE Electron Device Letters</i> , <b>2021</b> , 42, 216-219   | 4.4 | 5 |
| 66 | Accurate Analytical Switching-On Loss Model of SiC MOSFET Considering Dynamic Transfer Characteristic and Qgd. <i>IEEE Transactions on Power Electronics</i> , <b>2020</b> , 35, 12264-12273                     | 7.2 | 4 |
| 65 | GaN-on-Si lateral power devices with symmetric vertical leakage: The impact of floating substrate <b>2018</b> ,  |     | 4 |
| 64 | Surge capability of 1.2kV SiC diodes with high-temperature implantation 2018,  |     | 4 |
| 63 | Optimization of Bosch etch process for vertically stacked Si nanowires. <i>Journal of Materials Science: Materials in Electronics</i> , <b>2012</b> , 23, 334-342  | 2.1 | 4 |
| 62 | High-efficiency quasi-two-stage converter with current sharing for multi-channel LED driver 2013,  |     | 4 |
| 61 | Investigation on Surge Current Capability of 4H-SiC Trench-Gate MOSFETs in Third Quadrant Under Various VGS Biases. <i>IEEE Journal of Emerging and Selected Topics in Power Electronics</i> , <b>2020</b> , 1-1 | 5.6 | 4 |
| 60 | Degradation of 4H-SiC MOSFET body diode under repetitive surge current stress 2020,  |     | 4 |
| 59 | Switching Performance Evaluation of 1200 V Vertical GaN Power FinFETs <b>2019</b> ,  |     | 4 |
| 58 | A Wide Output LLC Converter Based on Full Bridge and Half Bridge Topology Morphing Method Using Trajectory Transition <b>2018</b> ,  |     | 4 |
| 57 | 1 kV/1.3 mltm2 vertical GaN-on-GaN Schottky barrier diodes with high switching performance <b>2018</b> ,   |     | 4 |
| 56 | Characterization of 1.2 kV SiC super-junction SBD implemented by trench and implantation technique <b>2018</b> ,   |     | 4 |
| 55 | Fabrication and testing of 3500V/15A SiC JFET based power module for high-voltage, high-frequency applications <b>2015</b> ,   |     | 3 |

| 54 | CMOS-compatible ehancement-mode GaN-on-Si MOS-HEMT with high breakdown voltage (930V) using thermal oxidation and TMAH wet etching <b>2015</b> ,   |     | 3 |
|----|--|-----|---|
| 53 | Modular multilevel power electronic transformer 2015,  |     | 3 |
| 52 | A Novel Self-Controlled Double Trench Gate Snapback Free Reverse-Conducting IGBT With a Built-in Trench Barrier Diode. <i>IEEE Transactions on Electron Devices</i> , <b>2020</b> , 67, 1705-1711  | 2.9 | 3 |
| 51 | A capacitor voltage balancing method for a three phase modular multilevel DC-DC converter 2017,  |     | 3 |
| 50 | Practical One-Step Solution of Smoothly Tapered Junction Termination Extension for High Voltage SiC Gate Turn-off Thyristor <b>2019</b> ,  |     | 3 |
| 49 | UIS Withstanding Capability of GaN E-HEMTs with Schottky and Ohmic p-GaN contact 2020,   |     | 3 |
| 48 | Investigation of Temperature-Dependent Dynamic RON of GaN HEMT with Hybrid-Drain under Hard and Soft Switching <b>2020</b> ,   |     | 3 |
| 47 | A Resonant DC-DC Converter with Modular Rectifier for High Voltage Gain and Wide Output Voltage Range Applications <b>2019</b> ,   |     | 3 |
| 46 | A Voltage Balancing Method for Series-Connected Power Devices in an LLC Resonant Converter. <i>IEEE Transactions on Power Electronics</i> , <b>2021</b> , 36, 3628-3632  | 7.2 | 3 |
| 45 | Photolithographic Patterning of Cytop with Limited Contact Angle Degradation. <i>Micromachines</i> , <b>2018</b> , 9,  | 3.3 | 3 |
| 44 | Design and Fabrication of 1.92 kV 4H-SiC Super-Junction SBD With Wide-Trench Termination. <i>IEEE Transactions on Electron Devices</i> , <b>2021</b> , 1-8   | 2.9 | 3 |
| 43 | The effect of h-BN buffer layers in bilayer graphene on Co (111). <i>Journal of the Korean Physical Society</i> , <b>2015</b> , 66, 1631-1636  | 0.6 | 2 |
| 42 | Novel Platform for Surface-Mediated Gene Delivery Assisted with Visible-Light Illumination. <i>ACS Applied Materials &amp; Delivery Assisted With Visible-Light Illumination and Applied Materials &amp; Delivery Assisted with Visible-Light Illumination and Applied Materials &amp; Delivery Assisted with Visible-Light Illumination and ACS Applied Materials &amp; Delivery Assisted with Visible-Light Illumination and ACS Applied Materials &amp; Delivery Assisted with Visible-Light Illumination and ACS Applied Materials &amp; Delivery Assisted with Visible-Light Illumination and ACS Applied Materials &amp; Delivery Assisted with Visible-Light Illumination and ACS Applied Materials &amp; Delivery Assisted with Visible-Light Illumination and ACS Applied Materials &amp; Delivery Assisted with Visible Applied William Applied Materials &amp; Delivery Assisted with Visible Applied William Applied Wi</i> | 9.5 | 2 |
| 41 | Design and Optimization of Vertical GaN PiN Diodes With Fluorine-Implanted Termination. <i>IEEE Journal of the Electron Devices Society</i> , <b>2020</b> , 8, 241-250   | 2.3 | 2 |
| 40 | Buffer leakage induced pre-breakdown mechanism for AlGaN/GaN HEMTs on Si 2013,   |     | 2 |
| 39 | Optimal design of SiC MOSFETs for 20kW DCDC converter <b>2017</b> ,  |     | 2 |
| 38 | Impact of common source inductance on switching loss of SiC MOSFET <b>2015</b> ,   |     | 2 |
| 37 | A 10kV/200A SiC MOSFET module with series-parallel hybrid connection <b>2014</b> ,   |     | 2 |

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| 36 | Sidewall-Implanted Trench Termination for 4H-SiC Devices With High Breakdown Voltage and Low Leakage Current. <i>IEEE Electron Device Letters</i> , <b>2022</b> , 43, 104-107              | 4.4 | 2 |
|----|--|-----|---|
| 35 | Vertical GaN power rectifiers: interface effects and switching performance. <i>Semiconductor Science and Technology</i> , <b>2020</b> , 36, 024005   | 1.8 | 2 |
| 34 | Understanding the breakdown asymmetry of 4H-SiC power diodes with extended defects at locations along step-flow direction. <i>Journal of Applied Physics</i> , <b>2020</b> , 128, 164501   | 2.5 | 2 |
| 33 | Plasma Spreading Layers: An Effective Method for Improving Surge and Avalanche Robustness of SiC Devices. <i>IEEE Transactions on Electron Devices</i> , <b>2021</b> , 1-8                 | 2.9 | 2 |
| 32 | Mechanism of Ti/Al/Ni/Au ohmic contacts to AlGaN/GaN heterostructures via laser annealing. <i>Chinese Physics B</i> , <b>2019</b> , 28, 037302   | 1.2 | 1 |
| 31 | High-voltage full-SiC power module: Device fabrication, testing and high frequency application in kW-level converter <b>2015</b> ,   |     | 1 |
| 30 | Modeling and Analysis of vgs Characteristics for Upper-Side and Lower-Side Switches at Turn-on Transients for a 1200V/200A Full-SiC Power Module. <i>Micromachines</i> , <b>2019</b> , 11, | 3.3 | 1 |
| 29 | Surge Current Capability of GaN E-HEMTs in Reverse Conduction Mode 2019,   |     | 1 |
| 28 | Low surface damage during ohmic contact formation in AlGaN/GaN HEMT by selective laser annealing. <i>Electronics Letters</i> , <b>2019</b> , 55, 658-660                                   | 1.1 | 1 |
| 27 | Design and Experimental Study of 1.2kV 4H-SiC Merged PiN Schottky Diode <b>2019</b> ,  |     | 1 |
| 26 | Resonant power electronic transformer for power grid <b>2014</b> ,   |     | 1 |
| 25 | PWAM control of bidirectional LLC resonant converter <b>2013</b> ,   |     | 1 |
| 24 | Single Pulse Avalanche Robustness and Analysis for 1200-V SiC Junction Barrier Schottky Diode <b>2020</b> ,  |     | 1 |
| 23 | Experimental Investigation on Failure Mechanism of SiC Power MOSFETs under Single Pulse Avalanche Stress <b>2020</b> ,   |     | 1 |
| 22 | Negative Dynamic RON in Vertical GaN PiN Diode: The Impact of Conductivity Modulation 2020,  |     | 1 |
| 21 | Investigation of Avalanche Capability of 1200V 4H-SiC MPS Diodes and JBS Diodes <b>2020</b> ,  |     | 1 |
| 20 | 1.2kV SiC Merged PiN Schottky Diode with Improved Surge Current Capability <b>2020</b> ,   |     | 1 |
| 19 | The Safe Operating Area of AlGaN/GaN-Based Sensor. <i>IEEE Sensors Journal</i> , <b>2021</b> , 21, 6241-6247   | 4   | 1 |

| 18 | The Impact of Process Conditions on Surge Current Capability of 1.2 kV SiC JBS and MPS Diodes. <i>Materials</i> , <b>2021</b> , 14,   | 3.5 | 1 |
|----|---|-----|---|
| 17 | Single-Mask Implantation-Free Technique Based on Aperture Density Modulation for Termination in High-Voltage SiC Thyristors. <i>IEEE Transactions on Electron Devices</i> , <b>2021</b> , 68, 1181-1184     | 2.9 | 1 |
| 16 | Design and Implement of 10 kV SiC JBS Based on Exponential Varying Field Limiting Rings 2018,   |     | 1 |
| 15 | Low limit of detection of the AlGaN/GaN-based sensor by the Kelvin connection detection technique. <i>Microsystems and Nanoengineering</i> , <b>2021</b> , 7, 51  | 7.7 | 1 |
| 14 | Performance analysis of 4H-SiC super-junction devices: impact of trench angle and improvement with multi-epi structure. <i>Semiconductor Science and Technology</i> , <b>2021</b> , 36, 105006              | 1.8 | 1 |
| 13 | Characterization and Analysis on Performance and Avalanche Reliability of SiC MOSFETs With Varied JFET Region Width. <i>IEEE Transactions on Electron Devices</i> , <b>2021</b> , 68, 3982-3990             | 2.9 | 1 |
| 12 | A Novel SiC LDMOS with Electric Field Optimization by Step Doping Technology 2020,  |     | 1 |
| 11 | Modeling and Optimization of Smoothly Tapered Junction Termination Extension for High-Voltage SiC BJTs and Thyristors by Simulation. <i>IEEE Transactions on Electron Devices</i> , <b>2022</b> , 1-7       | 2.9 | О |
| 10 | Understanding Turn-On Transients of SiC High-Power Modules: Drain-Source Voltage Plateau Characteristics. <i>Energies</i> , <b>2020</b> , 13, 3802  | 3.1 | O |
| 9  | Analytical Model and Optimization for SiC Floating Island Structure. <i>IEEE Transactions on Electron Devices</i> , <b>2021</b> , 68, 222-229   | 2.9 | O |
| 8  | Protection of isolated and active regions in AlGaN/GaN HEMTs using selective laser annealing*. <i>Chinese Physics B</i> , <b>2021</b> , 30, 097302  | 1.2 | O |
| 7  | A Voltage Balancing Method for Series-Connected Power Devices Based on Active Clamping in Voltage Source Converters. <i>IEEE Transactions on Power Electronics</i> , <b>2022</b> , 1-1                      | 7.2 | O |
| 6  | Correction to II rench Termination With SiO2-Encapsulated Dielectric for Near-Ideal Breakdown Voltage in 4H-SiC Devices [Dec 18 1900-1903]. <i>IEEE Electron Device Letters</i> , <b>2019</b> , 40, 353-353 | 4.4 |   |
| 5  | Investigation on Thermal Resistance and Capacitance Characteristics of a Highly Integrated Power Control Unit Module. <i>Electronics (Switzerland)</i> , <b>2021</b> , 10, 958                              | 2.6 |   |
| 4  | Methodology for Enhanced Surge Robustness of 1.2kV SiC MOSFET Body Diode. <i>IEEE Journal of Emerging and Selected Topics in Power Electronics</i> , <b>2021</b> , 1-1                                      | 5.6 |   |
| 3  | Characterization and Analysis of 4H-SiC Super Junction JFETs Fabricated by Sidewall Implantation. <i>IEEE Transactions on Electron Devices</i> , <b>2022</b> , 1-9  | 2.9 |   |
| 2  | Electrothermal Coupling Model with Distributed Heat Sources for Junction Temperature Calculation during Surges. <i>IEEE Transactions on Power Electronics</i> , <b>2022</b> , 1-1                           | 7.2 |   |
| 1  | The Impact of the Hexagonal and Circular Cell Designs on the Characteristics and Ruggedness for 4H-SiC MPS Diodes. <i>IEEE Transactions on Electron Devices</i> , <b>2022</b> , 69, 1226-1232               | 2.9 |   |